LM211-EP
DIFFERENTIAL COMPARATOR WITH STROBES

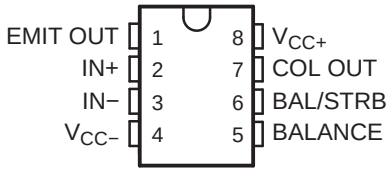
SLCS140A – DECEMBER 2002 – REVISED MAY 2006

FEATURES

- **Controlled Baseline**
  - **One Assembly/Test Site, One Fabrication Site**
- **Extended Temperature Performance of –55°C to 125°C**
- **Enhanced Diminishing Manufacturing Sources (DMS) Support**
- **Enhanced Product Change Notification**
- **Qualification Pedigree** (1)
- **Fast Response Times**
- **Strobe Capability**
- **Maximum Input Bias Current . . . 300 nA**
- **Maximum Input Offset Current . . . 70 nA**
- **Can Operate From Single 5-V Supply**

(1) Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold-compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

D PACKAGE
(TOP VIEW)



DESCRIPTION/ORDERING INFORMATION

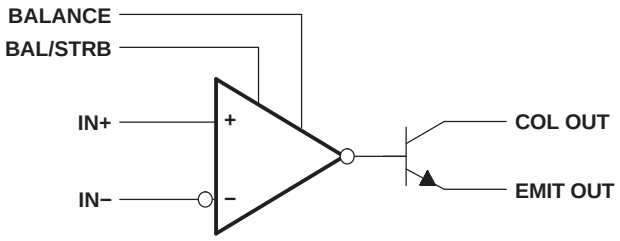
The LM211-EP is a single high-speed voltage comparator. This device is designed to operate from a wide range of power-supply voltages, including ±15-V supplies for operational amplifiers and 5-V supplies for logic systems. The output levels are compatible with most TTL and MOS circuits. This comparator is capable of driving lamps or relays and switching voltages up to 50 V at 50 mA. All inputs and outputs can be isolated from system ground. The outputs can drive loads referenced to ground, V_{CC+} or V_{CC-}. Offset balancing and strobe capabilities are available, and the outputs can be wired-OR connected. If the strobe is low, the output is in the off state, regardless of the differential input.

ORDERING INFORMATION

T_A	V_{IO} max AT 25°C	PACKAGE(1)		ORDERABLE PART NUMBER	TOP-SIDE MARKING
–40°C to 125°C	3 mV	SOIC – D	Tape and reel	LM211QDREP	LM211E
–55°C to 125°C	3 mV	SOIC – D	Tape and reel	LM211MDREP	LM211M

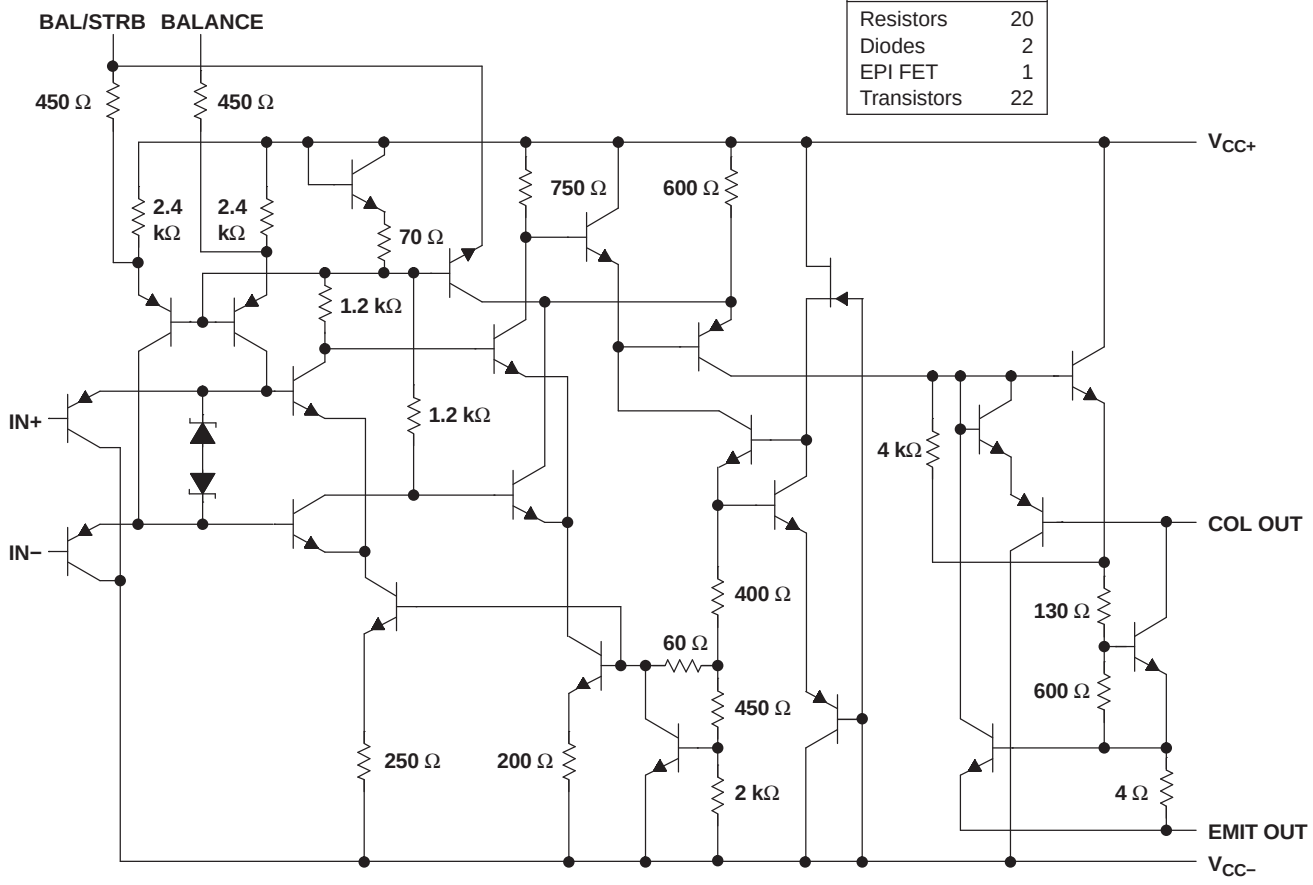
(1) Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

FUNCTIONAL BLOCK DIAGRAM



SCHEMATIC

Component Count	
Resistors	20
Diodes	2
EPI FET	1
Transistors	22



All resistor values shown are nominal.

Absolute Maximum Ratings(1)

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
V_{CC+}	Supply voltage(2)		18	V
V_{CC-}			–18	
$V_{CC+} - V_{CC-}$			36	
V_{ID}	Differential input voltage(3)		±30	V
V_I	Input voltage, either input(2)(4)		±15	V
	Voltage from emitter output to V_{CC-}		30	V
	Voltage from collector output to V_{CC-}		50	V
	Duration of output short circuit(5)		10	s
T_J	Junction temperature		148	°C
θ_{JA}	Package thermal impedance(6)		97	°C/W
	Lead temperature 1,6 mm (1/16 in) from case for 10 s		260	°C
T_{stg}	Storage temperature range(7)	–65	150	°C

(1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
(2) All voltage values, unless otherwise noted, are with respect to the midpoint between V_{CC+} and V_{CC-}.
(3) Differential voltages are at IN+ with respect to IN–.
(4) The magnitude of the input voltage must never exceed the magnitude of the supply voltage or ±15 V, whichever is less.
(5) The output may be shorted to ground or either power supply.
(6) The package thermal impedance is calculated in accordance with JESD 51-7.
(7) Long-term high–temperature storage and/or extended use at maximum recommended operating conditions may result in a reduction of overall device life. See http://www.ti.com/ep_quality for additional information on enhanced plastic packaging.

Recommended Operating Conditions

		MIN	MAX	UNIT
$V_{CC+} - V_{CC-}$	Supply voltage	3.5	30	V
V_I	Input voltage ($\lvert V_{CC+} \rvert \le 15$ V)	V_{CC-} + 0.5	V_{CC+} – 1.5	V
T_A	Operating free-air temperature range for Q temp	–40	125	°C
T_A	Operating free-air temperature range for M temp	–55	125	°C

Electrical Characteristics

at specified free-air temperatures of Q and M temp ranges, V_{CC+} = ±15 V (unless otherwise noted)

PARAMETER		TEST CONDITIONS		T_A (1)	MIN	TYP (2)	MAX	UNIT
V_{IO}	Input offset voltage (3)			25°C		0.7	3	mV
				Full range			4	
I_{IO}	Input offset current (3)			25°C		4	10	nA
				Full range			20	
I_{IB}	Input bias current	V_O = 1 V to 14 V		25°C		75	100	nA
				Full range			150	
$I_{IL(S)}$	Low-level strobe current (4)	$V_{(strobe)}$ = 0.3 V,	$V_{ID} \leq$ – 10 mV	25°C		–3		mA
V_{ICR}	Common-mode input voltage range			Full range	13 to –14.5	13.8 to –14.7		V
A_{VD}	Large-signal differential voltage amplification	V_O = 5 V to 35 V,	R_L = 1 kΩ	25°C	40	200		V/mV
I_{OH}	High-level (collector) output leakage current	$I_{(strobe)}$ = –3 mA, V_{ID} = 5 mV	V_{OH} = 35 V,	25°C		0.2	10	nA
				Full range			0.5	µA
V_{OL}	Low-level (collector-to-emitter) output voltage	I_{OL} = 50 mA,	V_{ID} = –5 mV	25°C		0.75	1.5	V
		V_{CC+} = 4.5 V, I_{OL} = 8 mA,	$V_{CC–}$ = 0, V_{ID} = –6 mV	Full range		0.23	0.4	
I_{CC+}	Supply current from V_{CC+}, output low	V_{ID} = –10 mV,	No load	25°C		5.1	6	mA
$I_{CC–}$	Supply current from $V_{CC–}$, output high	V_{ID} = 10 mV,	No load	25°C		–4.1	–5	mA

(1) Unless otherwise noted, all characteristics are measured with BALANCE and BAL/STRB open and EMIT OUT grounded. Full range is –40°C to 125°C for Q temp and -55°C to 125°C for M temp.
(2) All typical values are at T_A = 25°C.
(3) The offset voltages and offset currents given are the maximum values required to drive the collector output up to 14 V or down to 1 V with a pullup resistor of 7.5 kΩ to V_{CC+}. These parameters actually define an error band and take into account the worst-case effects of voltage gain and input impedance.
(4) The strobe should not be shorted to ground; it should be current driven at –3 mA to –5 mA (see Figure 13 and Figure 27).

Switching Characteristics

V_{CC+} = ±15 V, T_A = 25°C

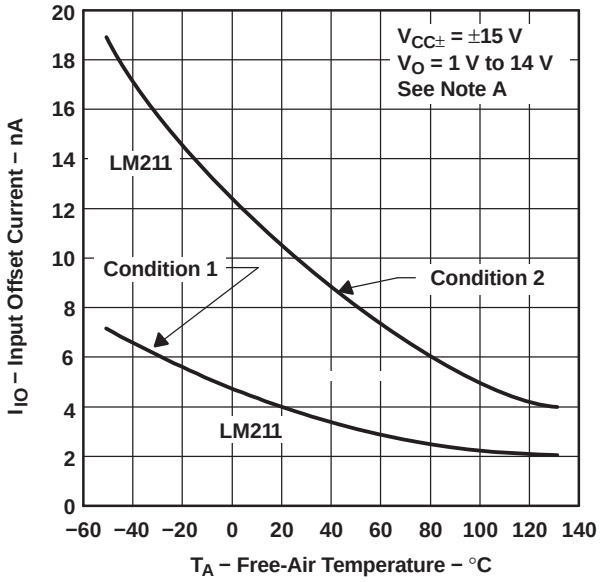
PARAMETER	TEST CONDITIONS		TYP	UNIT
Response time, low-to-high-level output	R_C = 500 Ω to 5 V,	C_L = 5 pF (1)	115	ns
Response time, high-to-low-level output	R_C = 500 Ω to 5 V,	C_L = 5 pF (1)	165	ns

(1) The response time specified is for a 100-mV input step with 5-mV overdrive and is the interval between the input step function and the instant when the output crosses 1.4 V.

TYPICAL CHARACTERISTICS

Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.

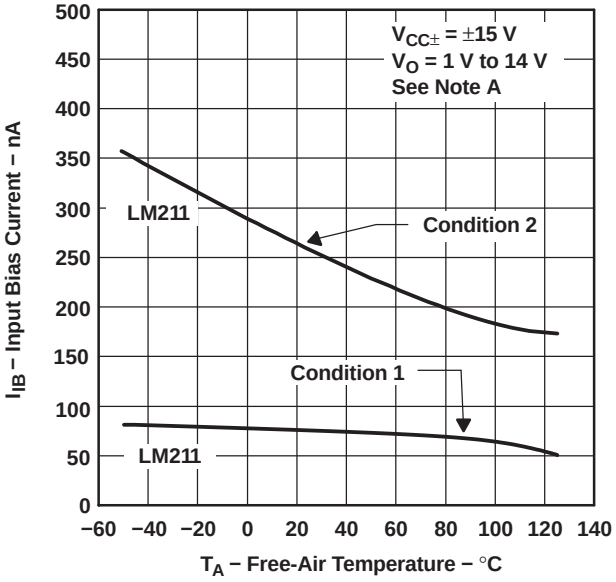
INPUT OFFSET CURRENT vs FREE-AIR TEMPERATURE



NOTE A: Condition 1 is with BALANCE and BAL/STRB open. Condition 2 is with BALANCE and BAL/STRB connected to V_{CC+}.

Figure 1.

INPUT BIAS CURRENT vs FREE-AIR TEMPERATURE

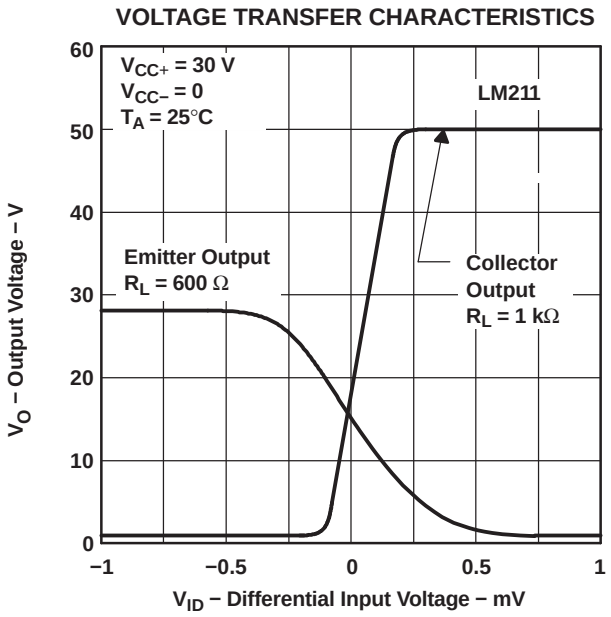


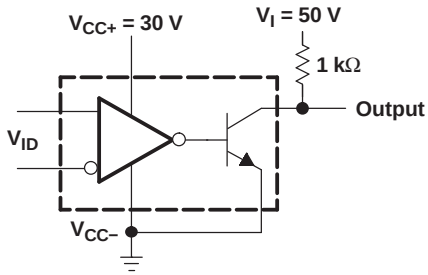
NOTE A: Condition 1 is with BALANCE and BAL/STRB open. Condition 2 is with BALANCE and BAL/STRB connected to V_{CC+}.

Figure 2.

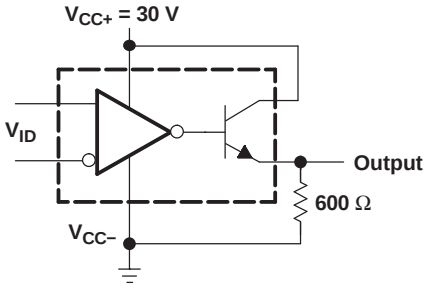
TYPICAL CHARACTERISTICS (continued)

Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.





COLLECTOR OUTPUT TRANSFER CHARACTERISTIC
TEST CIRCUIT FOR FIGURE 3



EMITTER OUTPUT TRANSFER CHARACTERISTIC
TEST CIRCUIT FOR FIGURE 3

Figure 3.

TYPICAL CHARACTERISTICS (continued)

Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.

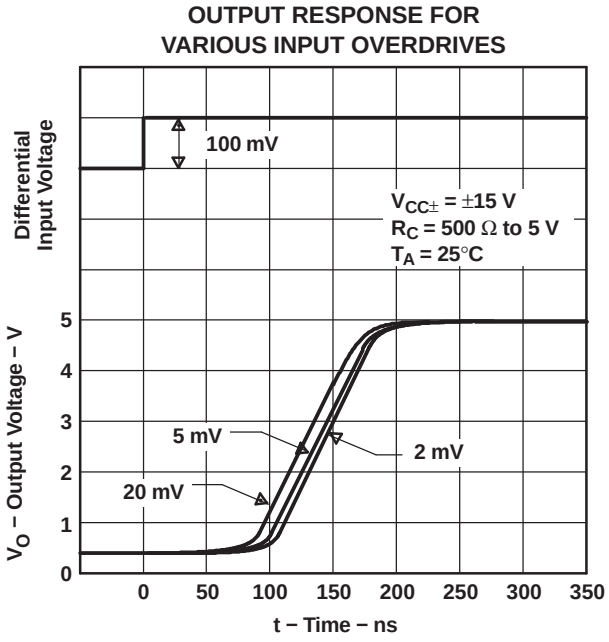


Figure 4.

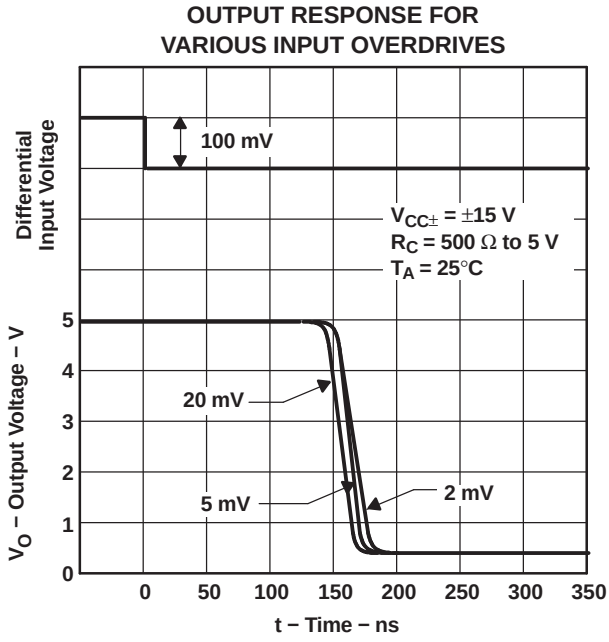
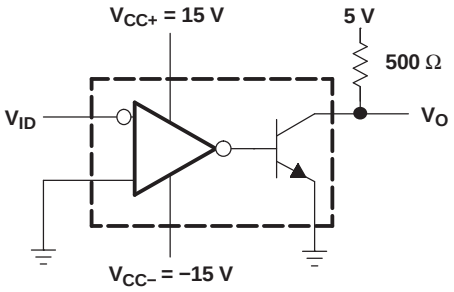


Figure 5.



TEST CIRCUIT FOR FIGURES 4 AND 5

TYPICAL CHARACTERISTICS (continued)

Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.

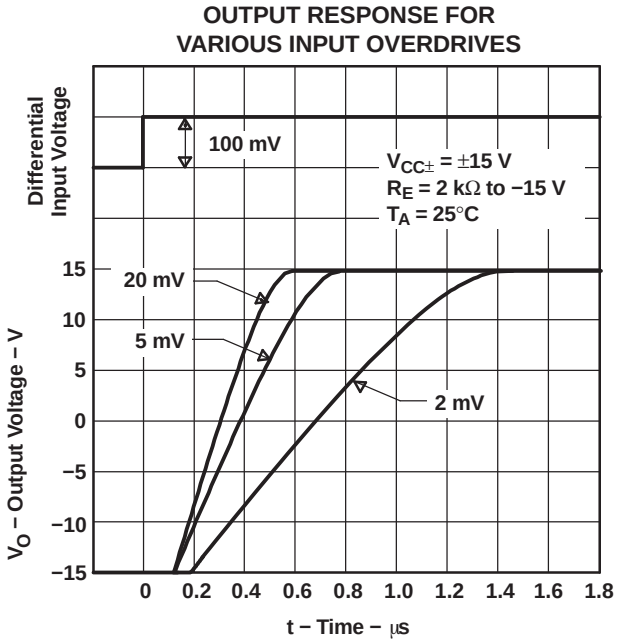


Figure 6.

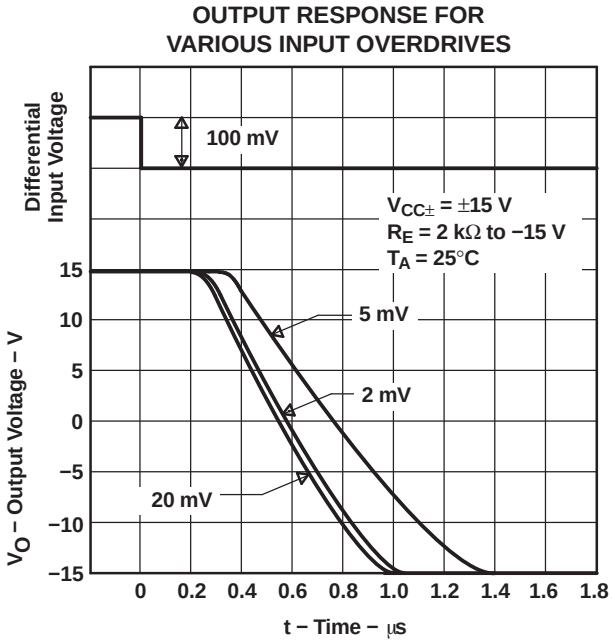
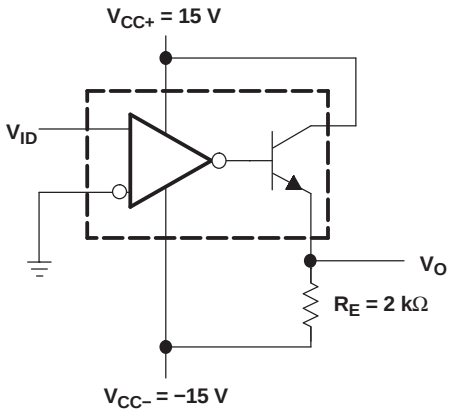


Figure 7.



TEST CIRCUIT FOR FIGURES 6 AND 7

TYPICAL CHARACTERISTICS (continued)

Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.

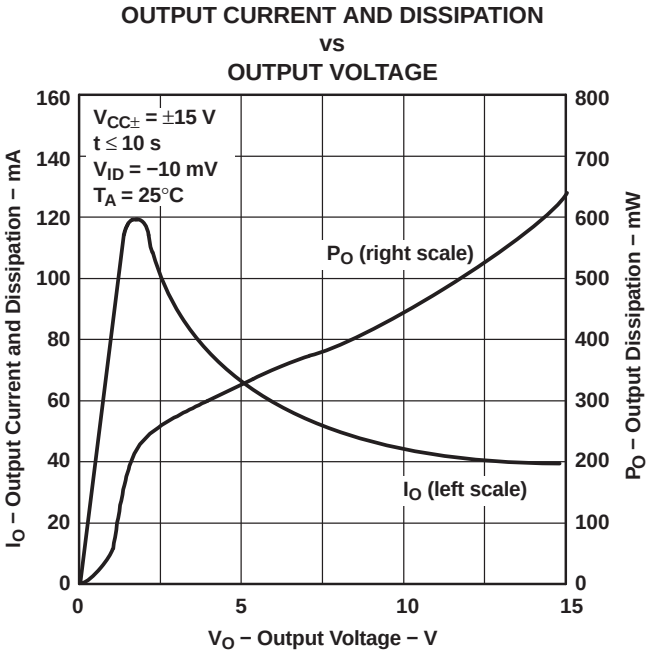


Figure 8.

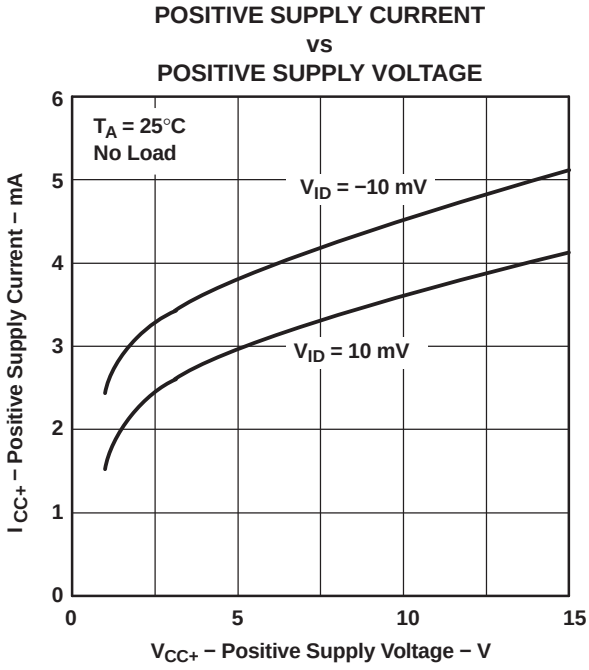


Figure 9.

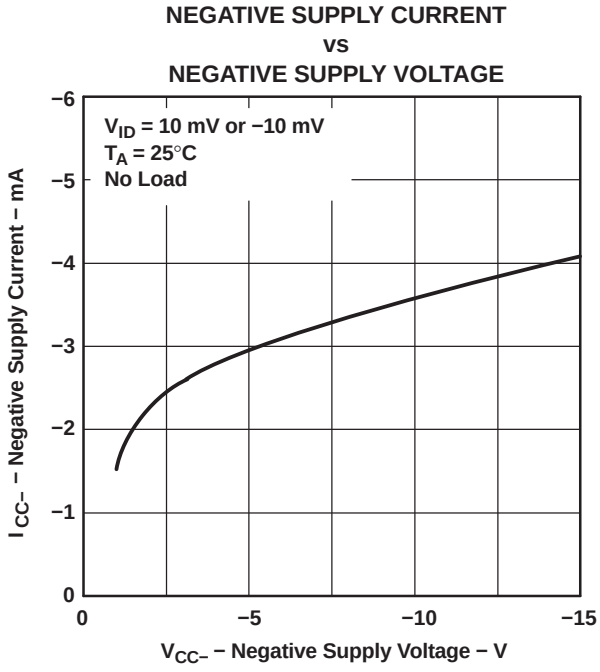


Figure 10.

APPLICATION INFORMATION

Figure 11 through Figure 29 show various applications for the LM211-EP comparator.

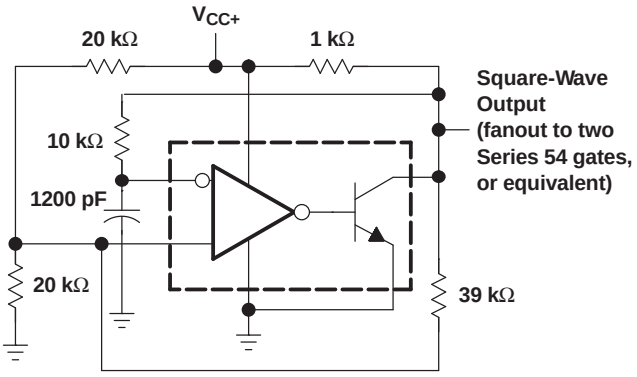
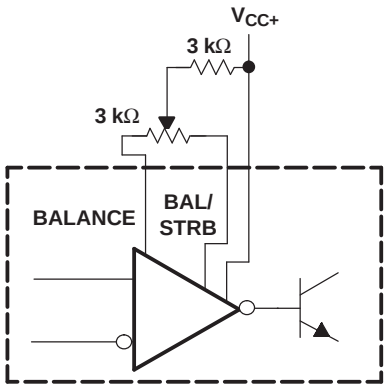


Figure 11. 100-kHz Free-Running Multivibrator



NOTE: If offset balancing is not used, the BALANCE and BAL/STRB pins should be shorted together.

Figure 12. Offset Balancing

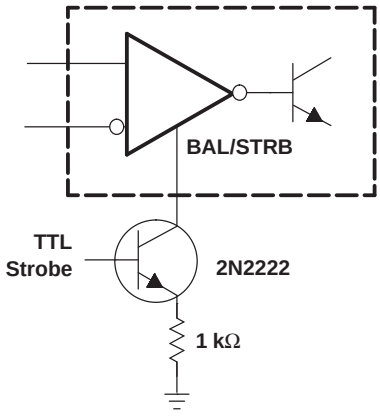


Figure 13. Strobing

APPLICATION INFORMATION (continued)

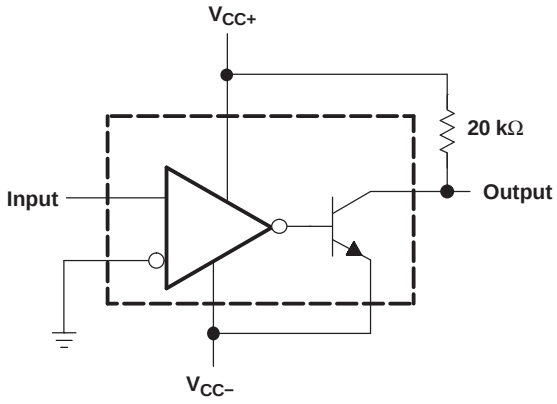
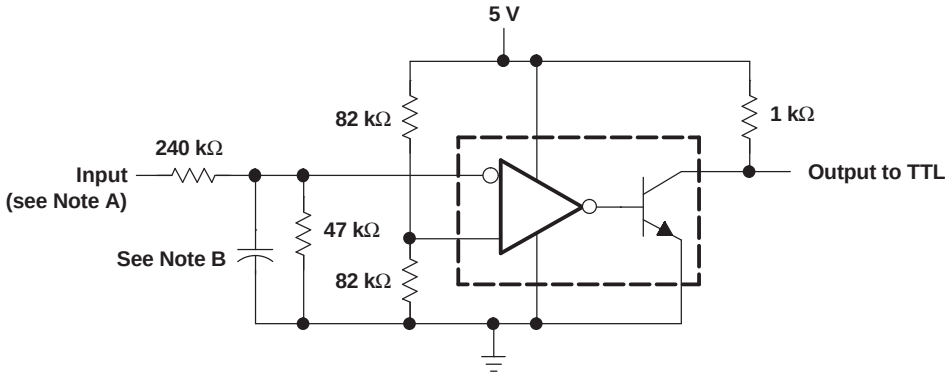


Figure 14. Zero-Crossing Detector



A. Resistor values shown are for a 0-to-30-V logic swing and a 15-V threshold.

B. May be added to control speed and reduce susceptibility to noise spikes

Figure 15. TTL Interface With High-Level Logic

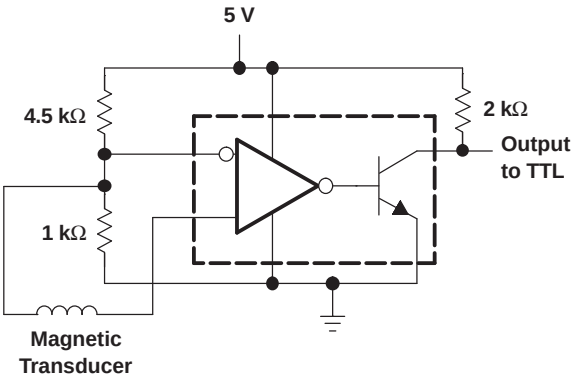


Figure 16. Detector for Magnetic Transducer

APPLICATION INFORMATION (continued)

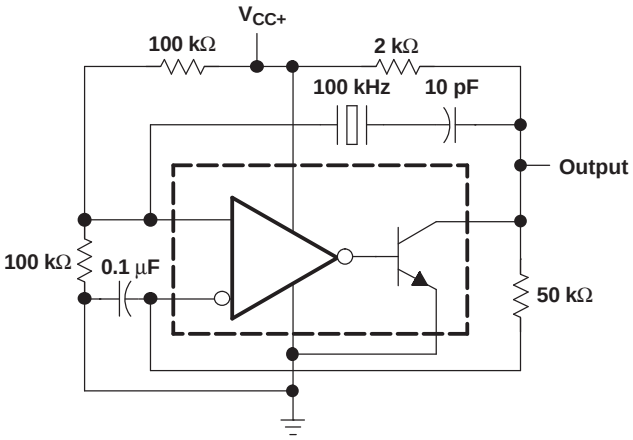


Figure 17. 100-kHz Crystal Oscillator

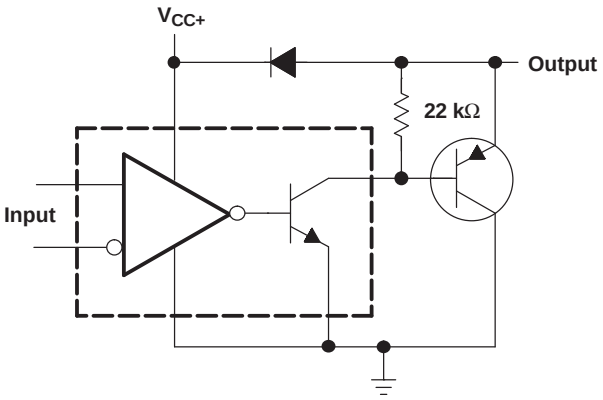
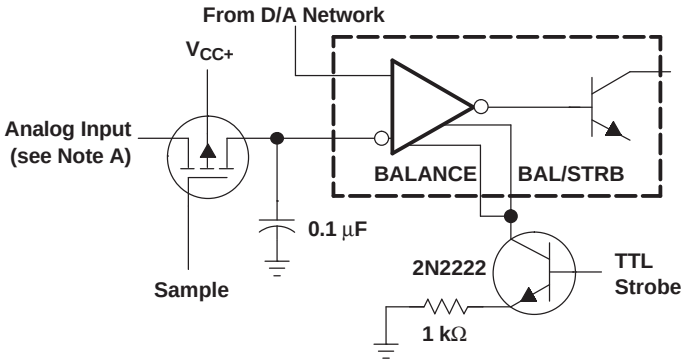


Figure 18. Comparator and Solenoid Driver



A. Typical input current is 50 pA with inputs strobed off.

Figure 19. Strobing Both Input and Output Stages Simultaneously

APPLICATION INFORMATION (continued)

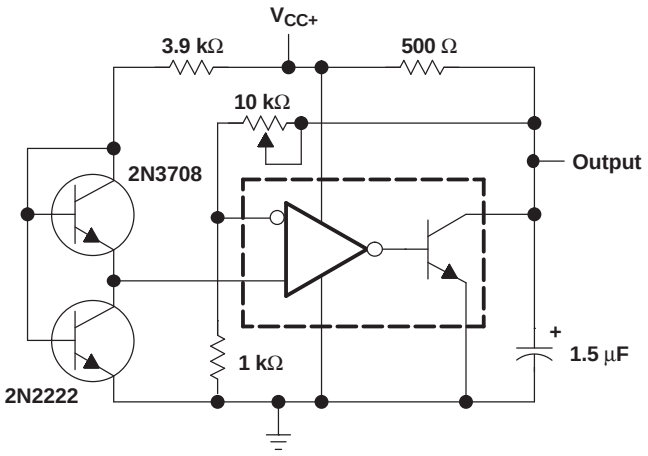


Figure 20. Low-Voltage Adjustable Reference Supply

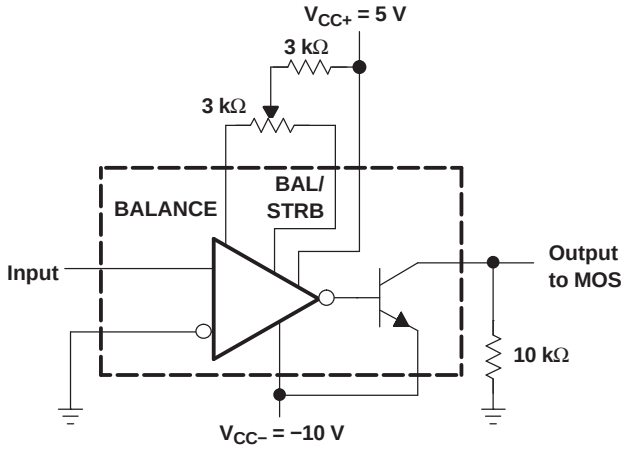
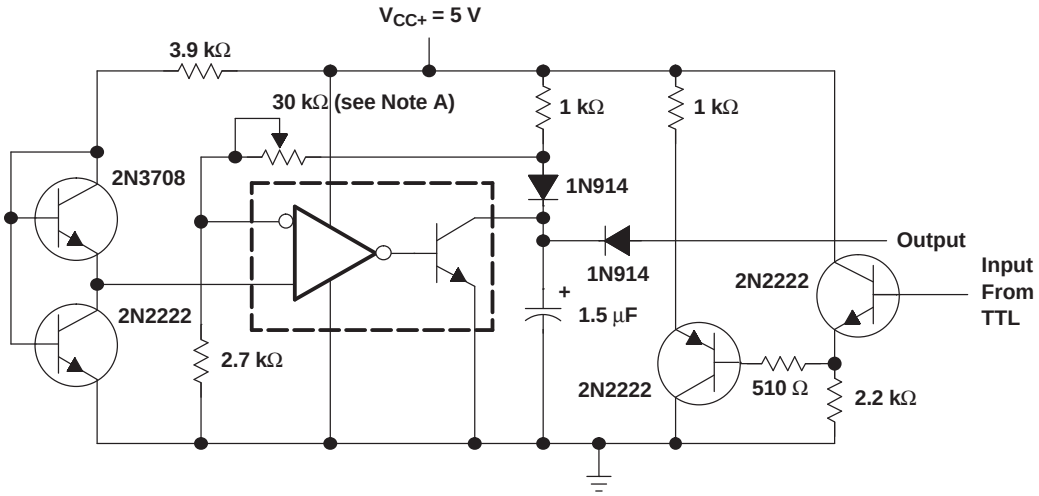


Figure 21. Zero-Crossing Detector Driving MOS Logic



A. Adjust to set clamp level

Figure 22. Precision Squarer

APPLICATION INFORMATION (continued)

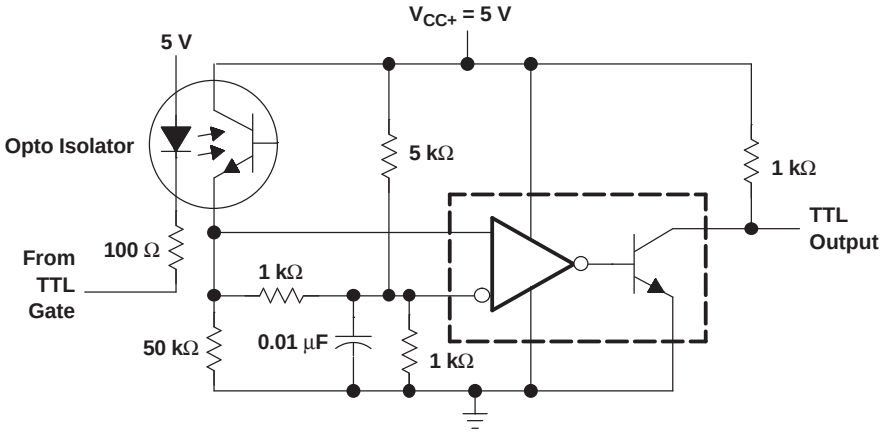


Figure 23. Digital Transmission Isolator

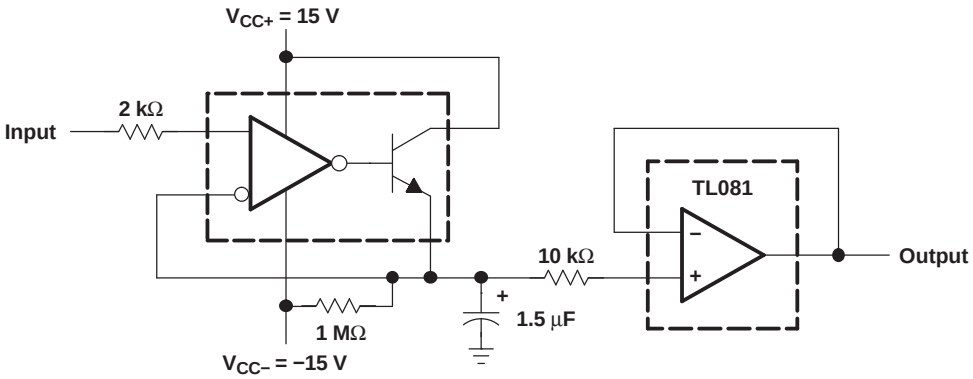


Figure 24. Positive-Peak Detector

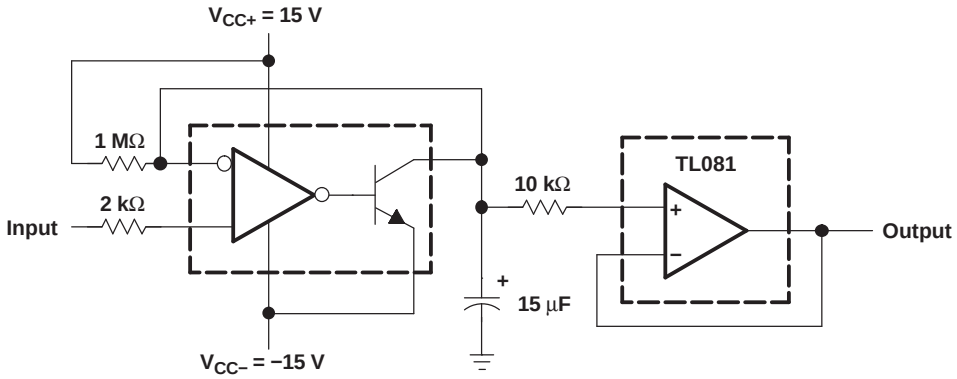
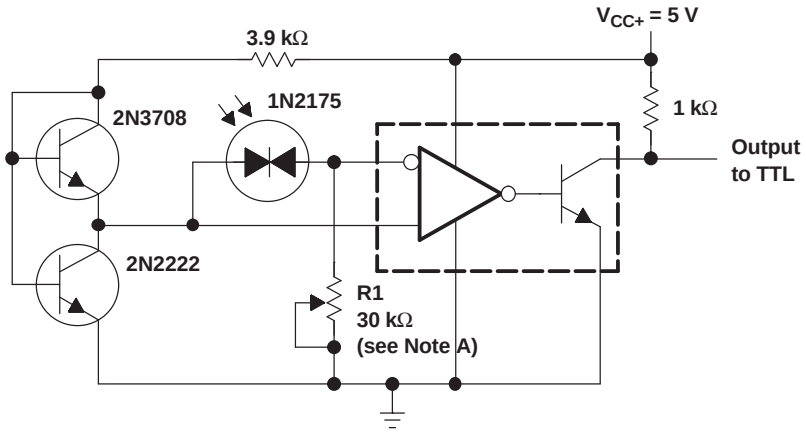


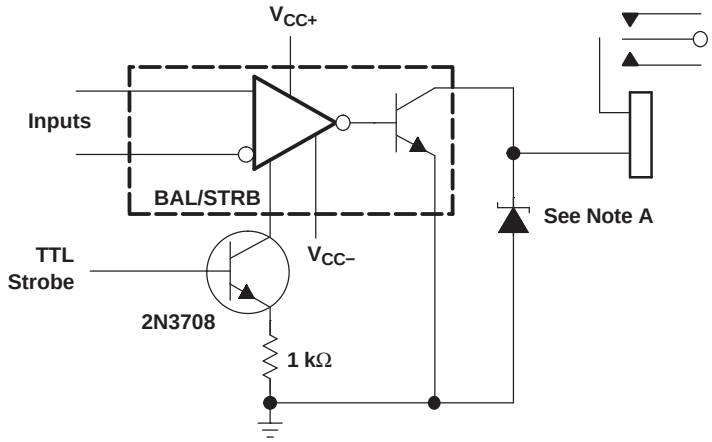
Figure 25. Negative-Peak Detector

APPLICATION INFORMATION (continued)



A. R1 sets the comparison level. At comparison, the photodiode has less than 5 mV across it, decreasing dark current by an order of magnitude.

Figure 26. Precision Photodiode Comparator



A. Transient voltage and inductive kickback protection

Figure 27. Relay Driver With Strobe

APPLICATION INFORMATION (continued)

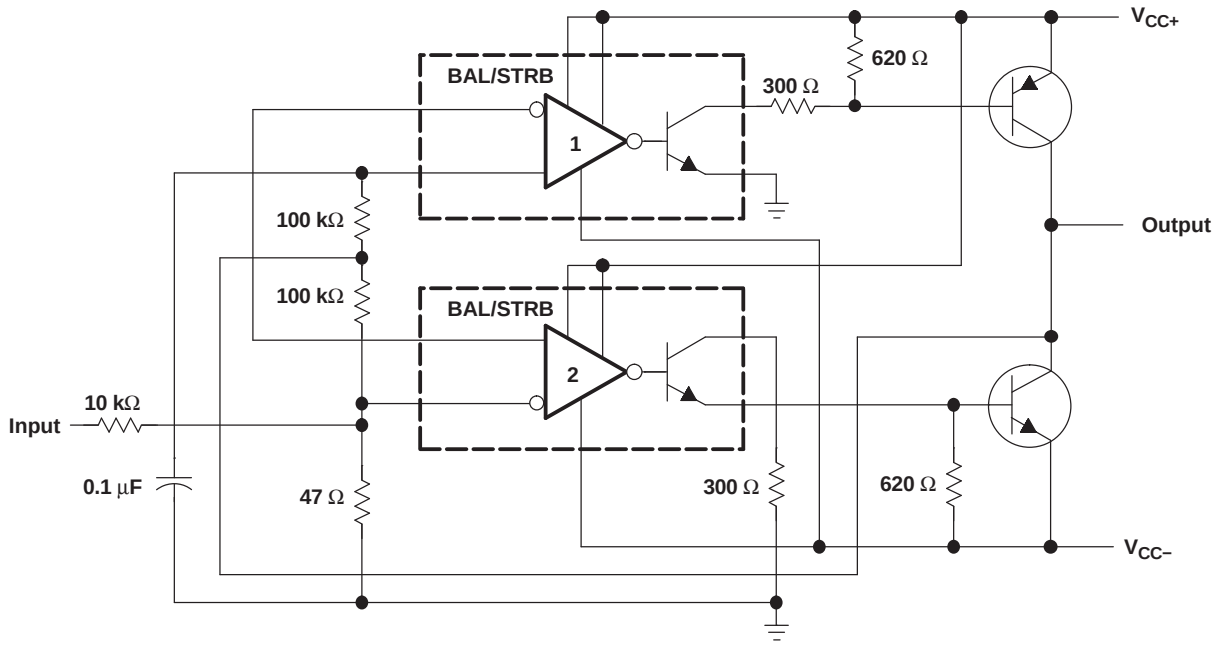


Figure 28. Switching Power Amplifier

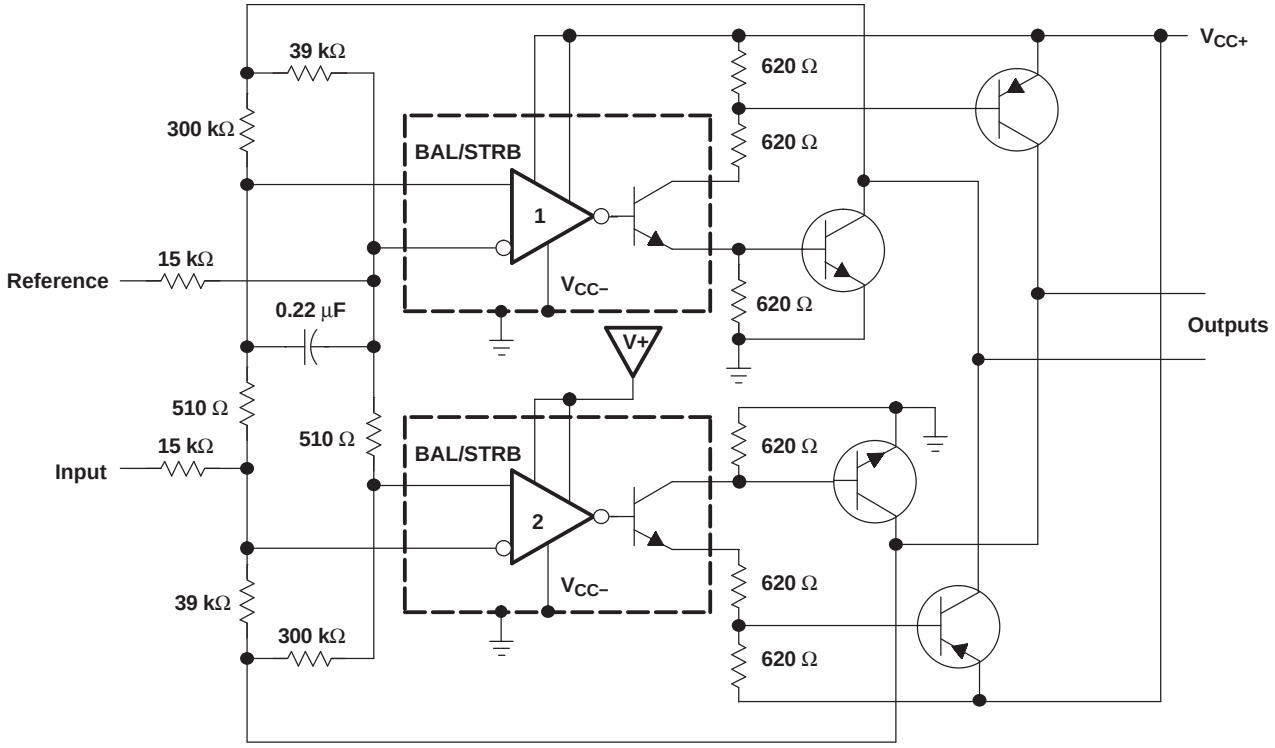


Figure 29. Switching Power Amplifiers

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package | Pins	Package qty | Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
LM211MDREP	Active	Production	SOIC (D) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	LM211M
LM211MDREP.A	Active	Production	SOIC (D) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	LM211M
LM211QDREP	Active	Production	SOIC (D) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LM211E
LM211QDREP.A	Active	Production	SOIC (D) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LM211E
V62/03638-01XE	Active	Production	SOIC (D) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LM211E
V62/03638-02XE	Active	Production	SOIC (D) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	LM211M

(1) **Status:** For more details on status, see our product life cycle.

(2) **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) **RoHS values:** Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

(4) **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

OTHER QUALIFIED VERSIONS OF LM211-EP :

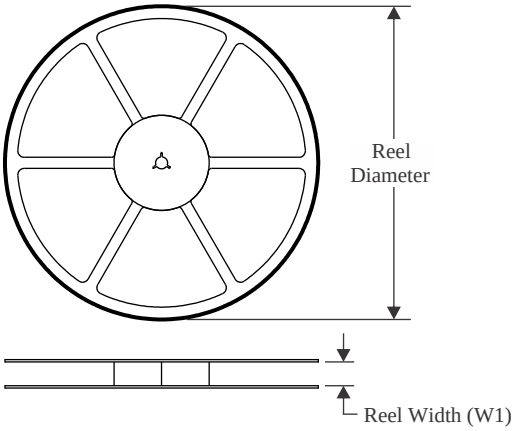
- Catalog : LM211
- Automotive : LM211-Q1

NOTE: Qualified Version Definitions:

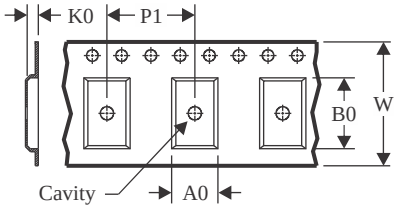
- Catalog - TI's standard catalog product
- Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

TAPE AND REEL INFORMATION

REEL DIMENSIONS

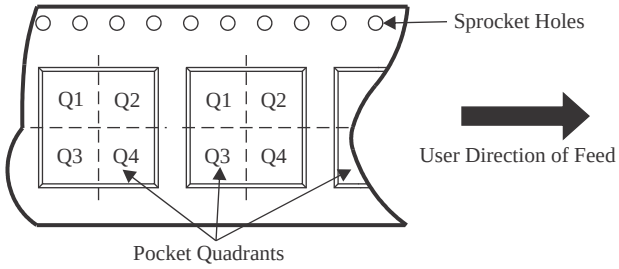


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

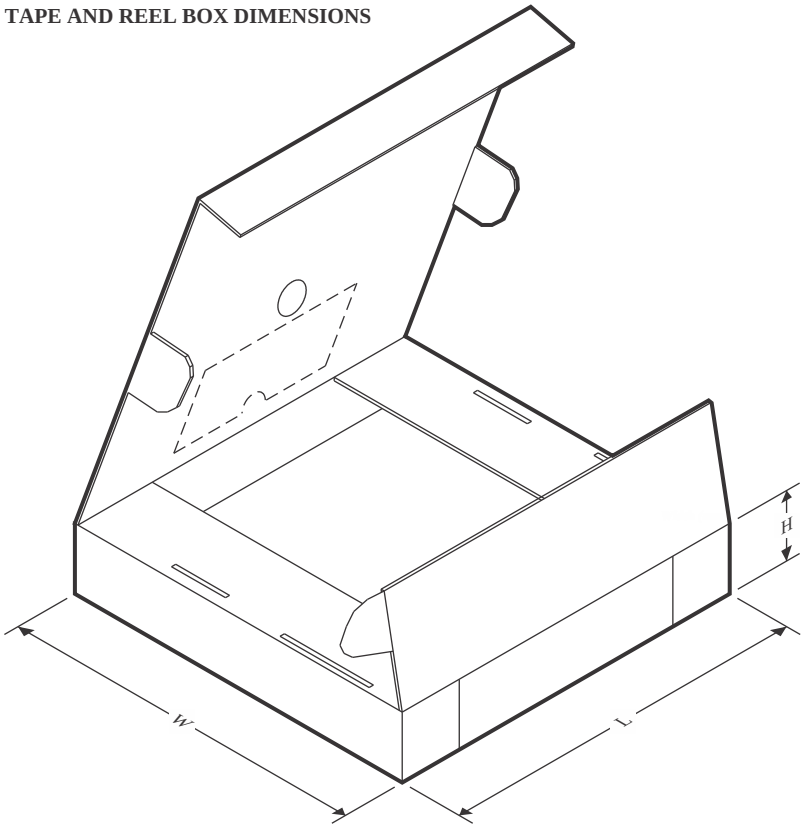
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

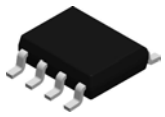
Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
LM211MDREP	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
LM211QDREP	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
LM211MDREP	SOIC	D	8	2500	353.0	353.0	32.0
LM211QDREP	SOIC	D	8	2500	340.5	338.1	20.6

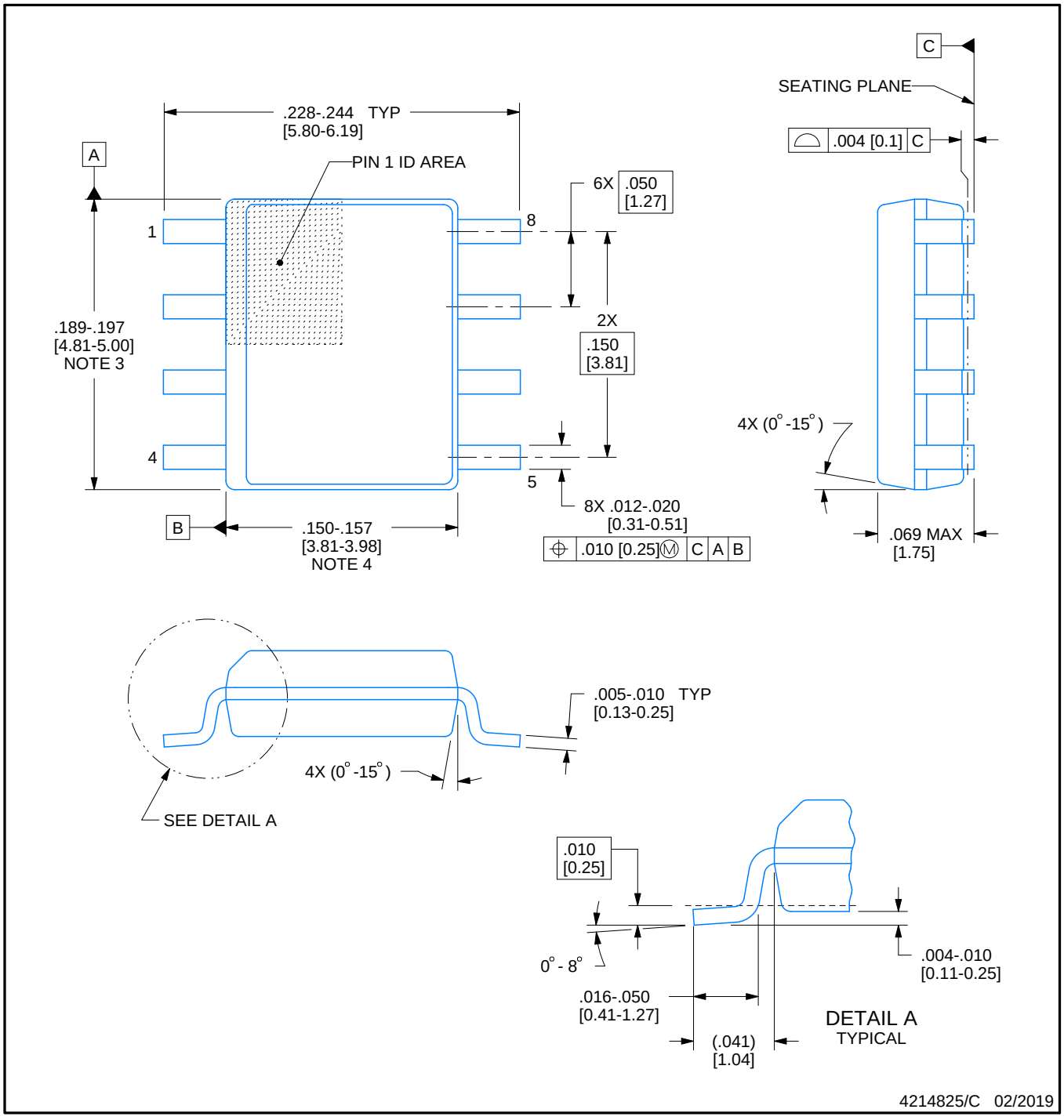


PACKAGE OUTLINE

D0008A

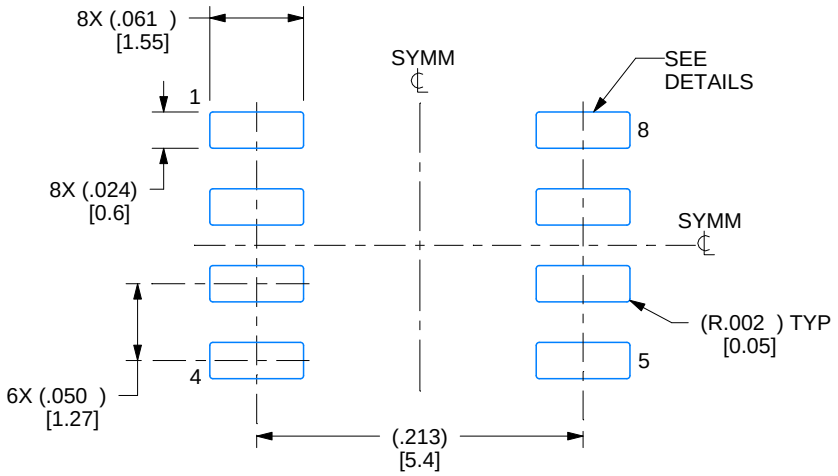
SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT

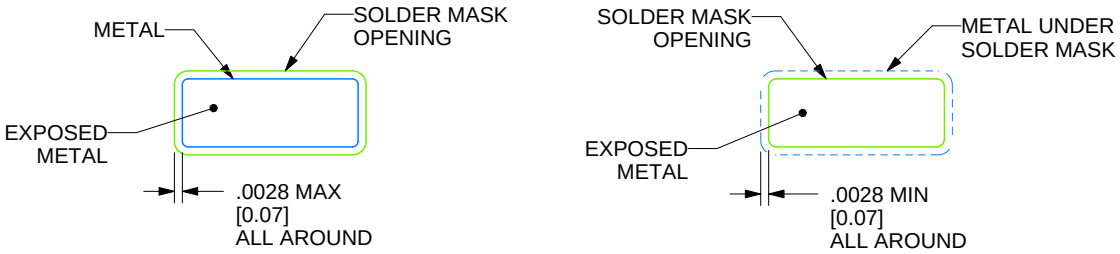


NOTES:

1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
4. This dimension does not include interlead flash.
5. Reference JEDEC registration MS-012, variation AA.



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:8X



SOLDER MASK DETAILS

4214825/C 02/2019

NOTES: (continued)

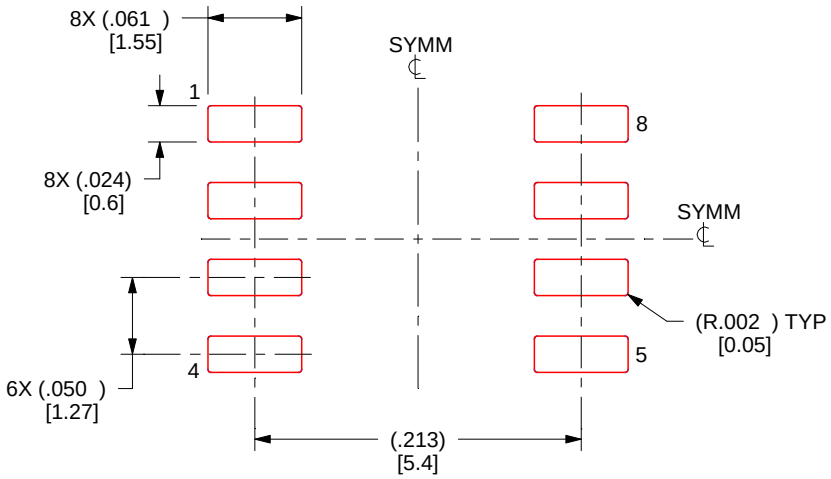
6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

D0008A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



SOLDER PASTE EXAMPLE
BASED ON .005 INCH [0.125 MM] THICK STENCIL
SCALE:8X

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NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

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